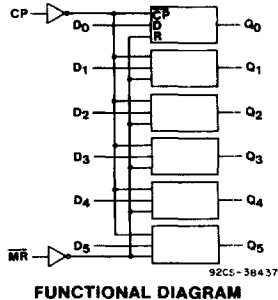


# CD54/74HC174 CD54/74HCT174

## High-Speed CMOS Logic



### Hex D-Type Flip-Flop with Reset Positive-Edge Triggered

**Type Features:**

- Buffered Positive-Edge-Triggered Clock
- Asynchronous Common Reset

The RCA-CD54/74HC174 and CD54/74HCT174 are edge triggered flip-flops which utilize silicon gate CMOS circuitry to implement D-type flip-flops. They possess low power and speeds comparable to low power Schottky TTL circuits. The devices contain 6 master-slave flip-flops with a common clock and common reset. Data on the D input having the specified setup and hold times is transferred to the Q output on the low to high transition of the CLOCK input. The MR input, when low, sets all outputs to a low state.

Each output can drive 10 low power Schottky TTL equivalent loads. The CD54/74HCT174 is functionally as well as pin compatible to the 54LS174/74LS174.

The CD54HC174 and CD54HCT174 are supplied in 16-lead hermetic dual-in-line ceramic packages (F suffix). The CD74HC174 and CD74HCT174 are supplied in 16-lead dual-in-line plastic packages (E suffix) and in 16-lead dual-in-line surface mount plastic packages (M suffix). Both types are also available in chip form (H suffix).

**Family Features:**

- Fanout (Over Temperature Range):  
Standard Outputs — 10 LSTTL Loads  
Bus Driver Outputs — 15 LSTTL Loads
- Wide Operating Temperature Range:  
CD74HC/HCT: -40 to +85°C
- Balanced Propagation and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- Alternate Source is Philips/Signetics
- CD54HC/CD74HC Types:  
2 to 6 V Operation  
High Noise Immunity:  
 $N_{IL} = 30\%$ ,  $N_{IH} = 30\%$  of  $V_{CC}$ ;  
@  $V_{CC} = 5 V$
- CD54HCT/CD74HCT Types:  
4.5 to 5.5 V Operation  
Direct LSTTL Input Logic Compatibility  
 $V_{IL} = 0.8 V$  max.,  $V_{IH} = 2 V$  Min.  
CMOS Input Compatibility  
 $I_I \leq 1 \mu A$  @  $V_{OL}$ ,  $V_{OH}$

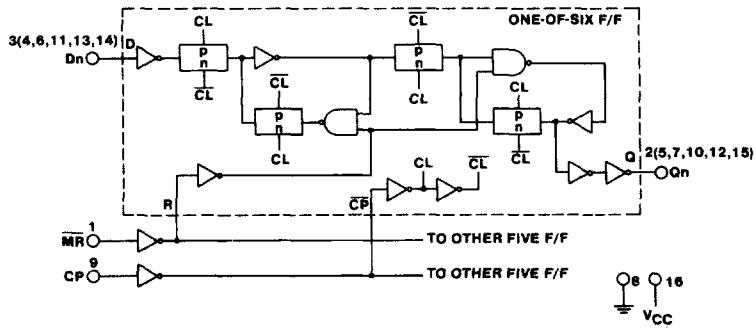


Fig. 1 — Logic diagram (Flip/Flop detail)

# CD54/74HC174 CD54/74HCT174

**MAXIMUM RATINGS, Absolute-Maximum Values:**

DC SUPPLY-VOLTAGE, (V<sub>cc</sub>):  
(Voltages referenced to ground) ..... -0.5 to +7 V

DC INPUT DIODE CURRENT, I<sub>IK</sub> (FOR V<sub>i</sub> < -0.5 V OR V<sub>i</sub> > V<sub>cc</sub> + 0.5 V) ..... ± 20 mA

DC OUTPUT DIODE CURRENT, I<sub>OL</sub> (FOR V<sub>o</sub> < -0.5 V OR V<sub>o</sub> > V<sub>cc</sub> + 0.5 V) ..... ± 20 mA

DC DRAIN CURRENT, PER OUTPUT (I<sub>o</sub>) (FOR -0.5 V < V<sub>o</sub> < V<sub>cc</sub> + 0.5 V) ..... ± 25 mA

DC V<sub>cc</sub> OR GROUND CURRENT (I<sub>cc</sub>): ..... ± 50 mA



POWER DISSIPATION PER PACKAGE (P<sub>o</sub>):  
For T<sub>A</sub> = -40 to +60°C (PACKAGE TYPE E) ..... 500 mW  
For T<sub>A</sub> = +60 to +85°C (PACKAGE TYPE E) ..... Derate Linearly at 8 mW/°C to 300 mW  
For T<sub>A</sub> = -55 to +100°C (PACKAGE TYPE F, H) ..... 500 mW  
For T<sub>A</sub> = +100 to +125°C (PACKAGE TYPE F, H) ..... Derate Linearly at 8 mW/°C to 300 mW  
For T<sub>A</sub> = -40 to +70°C (PACKAGE TYPE M) ..... 400 mW  
For T<sub>A</sub> = +70 to -125°C (PACKAGE TYPE M) ..... Derate Linearly at 6 mW/°C to 70 mW


OPERATING-TEMPERATURE RANGE (T<sub>A</sub>):  
PACKAGE TYPE F, H ..... -55 to +125°C  
PACKAGE TYPE E, M ..... -40 to +85°C

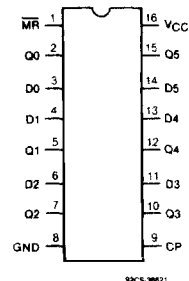
STORAGE TEMPERATURE (T<sub>stg</sub>) ..... -65 to +150°C

LEAD TEMPERATURE (DURING SOLDERING):  
At distance 1/16 ± 1/32 in. (1.59 ± 0.79 mm) from case for 10 s max. .... +265°C  
Unit inserted into a PC Board (min. thickness 1/16 in., 1.59 mm) with solder contacting lead tips only ..... +300°C

**TRUTH TABLE  
(EACH FLIP-FLOP)**

INPUTS			OUTPUTS
RESET (MR)	CLOCK CP	DATA D <sub>n</sub>	Q <sub>n</sub>
L	X	X	L
H		H	H
H		L	L
H	L	X	Q <sub>o</sub>

H = High Level (Steady State)  
L = Low Level (Steady State)  
X = Irrelevant  
 Transition from Low to High Level  
Q<sub>o</sub> = Level Before the Indicated Steady-State  
Input Conditions were established



**TOP VIEW  
TERMINAL ASSIGNMENT**

**RECOMMENDED OPERATING CONDITIONS:**

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	LIMITS		UNITS
	MIN.	MAX.	
Supply-Voltage Range (For T <sub>A</sub> = Full Package Temperature Range) V <sub>cc</sub> :* CD54/74HC Types CD54/74HCT Types	2 4.5	6 5.5	V
DC Input or Output Voltage V <sub>i</sub> , V <sub>o</sub>	0	V <sub>cc</sub>	V
Operating Temperature T <sub>A</sub> : CD74 Types CD54 Types	-40 -55	+85 +125	°C
Input Rise and Fall Times, t <sub>r</sub> , t <sub>f</sub> at 2 V at 4.5 V at 6 V	0 0 0	1000 500 400	ns

\*Unless otherwise specified, all voltages are referenced to Ground.

# CD54/74HC174 CD54/74HCT174

## STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CD74HC174/CD54HC174										CD74HCT174/CD54HCT174										UNITS	
	TEST CONDITIONS			74HC/54HC TYPE			74HC TYPE		54HC TYPE			TEST CONDITIONS		74HCT/54HCT TYPE			74HCT TYPE		54HCT TYPE			
	V <sub>I</sub> V	I <sub>O</sub> mA	V <sub>CC</sub> V	+25°C			-40/ +85°C		-55/ +125°C			V <sub>I</sub> V	V <sub>CC</sub> V	+25°C			-40/ +85°C		-55/ +125°C			
				Min	Typ	Max	Min	Max	Min	Max	Min			Max	Min	Typ	Max	Min	Max	Min		Max
High-Level Input Voltage V <sub>IH</sub>			2	1.5	—	—	1.5	—	1.5	—	—	4.5	to	2	—	—	2	—	2	—	V	
			4.5	3.15	—	—	3.15	—	3.15	—	—	5.5										
			6	4.2	—	—	4.2	—	4.2	—												
Low-Level Input Voltage V <sub>IL</sub>			2	—	—	0.5	—	0.5	—	0.5	—	4.5	to	—	—	0.8	—	0.8	—	0.8	V	
			4.5	—	—	1.35	—	1.35	—	1.35	—	5.5										
			6	—	—	1.8	—	1.8	—	1.8	—											
High-Level Output Voltage V <sub>OH</sub>	V <sub>IL</sub> or V <sub>IH</sub>	-0.02	2	1.9	—	—	1.9	—	1.9	—	V <sub>IL</sub> or V <sub>IH</sub>	4.5	4.4	—	—	4.4	—	4.4	—	4.4	V	
CMOS Loads			4.5	4.4	—	—	4.4	—	4.4	—		4.5										
			6	5.9	—	—	5.9	—	5.9	—												
TTL Loads	V <sub>IL</sub> or V <sub>IH</sub>										V <sub>IL</sub> or V <sub>IH</sub>	4.5	3.98	—	—	3.84	—	3.7	—		V	
			-4	4.5	3.98	—	—	3.84	—	3.7	—											
			-5.2	6	5.48	—	—	5.34	—	5.2	—											
Low-Level Output Voltage V <sub>OL</sub>	V <sub>IL</sub> or V <sub>IH</sub>	0.02	2	—	—	0.1	—	0.1	—	0.1	V <sub>IL</sub> or V <sub>IH</sub>	4.5	—	—	0.1	—	0.1	—	0.1	—	0.1	V
CMOS Loads			4.5	—	—	0.1	—	0.1	—	0.1												
			6	—	—	0.1	—	0.1	—	0.1												
TTL Loads	V <sub>IL</sub> or V <sub>IH</sub>										V <sub>IL</sub> or V <sub>IH</sub>	4.5	—	—	0.26	—	0.33	—	0.4	—	0.4	V
			4	4.5	—	—	0.26	—	0.33	—	0.4											
			5.2	6	—	—	0.26	—	0.33	—	0.4											
Input Leakage Current I <sub>I</sub>	V <sub>CC</sub> or Gnd		6	—	—	±0.1	—	±1	—	±1	Any Voltage Between V <sub>CC</sub> & Gnd	5.5	—	—	±0.1	—	±1	—	±1	—	±1	μA
Quiescent Device Current I <sub>CC</sub>	V <sub>CC</sub> or Gnd	0	6	—	—	8	—	80	—	160	V <sub>CC</sub> or Gnd	5.5	—	—	8	—	80	—	160	—	160	μA
Additional Quiescent Device Current per input pin. 1 unit load ΔI <sub>CC</sub> *											V <sub>CC</sub> -2.1	4.5 to 5.5	—	100	360	—	450	—	490	—	490	μA

\*For dual-supply systems theoretical worst case (V<sub>I</sub> = 2.4 V, V<sub>CC</sub> = 5.5 V) specification is 1.8 mA.

HCT Input Loading Table

Input	Unit Loads*
CP	0.80
MR	0.55
D	0.15

\*Unit load is ΔI<sub>CC</sub> limit specified in Static Characteristic Chart, e.g., 360 μA max. @ 25°C.

# CD54/74HC174 CD54/74HCT174

## PREREQUISITE FOR SWITCHING FUNCTION

CHARACTERISTIC	TEST CONDITION	LIMITS												UNITS
		25°C				-40°C to +85°C				-55°C to +125°C				
		HC		HCT		74HC		74HCT		54HC		54HCT		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Clock Pulse Width $t_w$ Fig. 3	2	80	—	—	—	100	—	—	—	120	—	—	—	ns
	4.5	16	—	20	—	20	—	25	—	24	—	30	—	
	6	14	—	—	—	17	—	—	—	20	—	—	—	
$\overline{\text{MR}}$ Pulse Width $t_w$ Fig. 4	2	80	—	—	—	100	—	—	—	120	—	—	—	ns
	4.5	16	—	25	—	20	—	31	—	24	—	38	—	
	6	14	—	—	—	17	—	—	—	20	—	—	—	
Setup Time Data to Clock $t_{SU}$ Fig. 5	2	60	—	—	—	75	—	—	—	90	—	—	—	ns
	4.5	12	—	16	—	15	—	20	—	18	—	24	—	
	6	10	—	—	—	13	—	—	—	15	—	—	—	
Hold Time Data to Clock $t_H$ Fig. 5	2	5	—	—	—	5	—	—	—	5	—	—	—	ns
	4.5	5	—	5	—	5	—	5	—	5	—	5	—	
	6	5	—	—	—	5	—	—	—	5	—	—	—	
Removal Time $\overline{\text{MR}}$ to Clock $t_{rem}$ Fig. 4	2	5	—	—	—	5	—	—	—	5	—	—	—	ns
	4.5	5	—	12	—	5	—	15	—	5	—	18	—	
	6	5	—	—	—	5	—	—	—	5	—	—	—	
Clock Frequency $f_{max}$	2	6	—	—	—	5	—	—	—	4	—	—	—	MHz
	4.5	30	—	25	—	24	—	20	—	20	—	17	—	
	6	35	—	—	—	28	—	—	—	24	—	—	—	

## SWITCHING CHARACTERISTICS ( $C_L = 50$ pF, Input $t_r = 6$ ns)

CHARACTERISTIC	TEST CONDITION	LIMITS												UNITS
		25°C				-40°C to +85°C				-55°C to +125°C				
		HC		HCT		74HC		74HCT		54HC		54HCT		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Propagation Delay Clock to Q $t_{PLH}$ $t_{PHL}$ Fig. 3	2	—	165	—	—	—	205	—	—	—	250	—	—	ns
	4.5	—	33	—	40	—	41	—	50	—	50	—	60	
	6	—	28	—	—	—	35	—	—	—	43	—	—	
Propagation Delay $\overline{\text{MR}}$ to Q $t_{PLH}$ $t_{PHL}$ Fig. 4	2	—	150	—	—	—	190	—	—	—	225	—	—	ns
	4.5	—	30	—	44	—	38	—	55	—	45	—	66	
	6	—	26	—	—	—	33	—	—	—	38	—	—	
Output Transition Time $t_{TLH}$ $t_{THL}$ Fig. 6	2	—	75	—	—	—	95	—	—	—	110	—	—	ns
	4.5	—	15	—	15	—	19	—	19	—	22	—	22	
	6	—	13	—	—	—	16	—	—	—	19	—	—	
Input Capacitance $C_{IN}$		—	10	—	10	—	10	—	10	—	10	—	10	pF

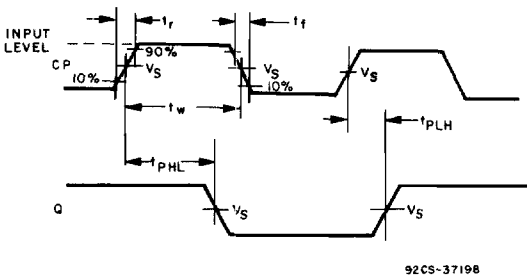
# CD54/74HC174 CD54/74HCT174

SWITCHING CHARACTERISTICS ( $V_{CC} = 5\text{ V}$ ,  $T_A = 25^\circ\text{C}$ , Input  $t_i = 6\text{ ns}$ )

CHARACTERISTIC	$t_{PLH}$	$C_L$ (pF)	Typical Values		UNITS
			HC	HCT	
Propagation Delay — Clock to Q Fig.3	$t_{PLH}$	15	13	17	ns
Propagation Delay — MR to Q Fig. 4	$t_{PLH}$	15	12	18	ns
Power Dissipation Capacitance*	$C_{PD}$	—	38	44	pF

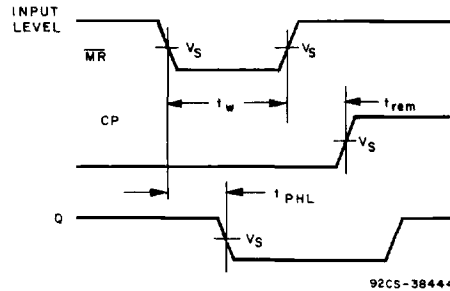
\* $C_{PD}$  is used to determine the dynamic power consumption, per flip-flop.

$P_D = C_{PD} V_{CC}^2 f_i + \Sigma (C_L V_{CC}^2 f_o)$  where:  $f_i$  = input frequency,  $f_o$  = output frequency,  
 $C_L$  = output load capacitance,  $V_{CC}$  = supply voltage



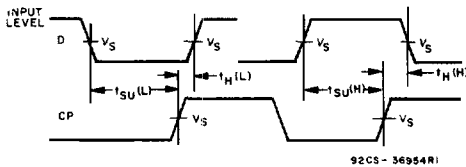
	54/74HC	54/74HCT
Input Level	$V_{CC}$	3 V
$V_S$	50% $V_{CC}$	1.3 V

Fig. 3 — Propagation delay times and clock pulse width.



	54/74HC	54/74HCT
Input Level	$V_{CC}$	3 V
$V_S$	50% $V_{CC}$	1.3 V

Fig. 4 — Prerequisite and propagation delay times for master reset.



	54/74HC	54/74HCT
Input Level	$V_{CC}$	3 V
$V_S$	50% $V_{CC}$	1.3 V

Fig. 5 — Pre

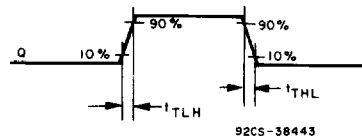


Fig. 6 — Transition times.